


Search Notes 	Application/Control No. 10656846	Applicant(s)/Patent Under Reexamination CHU ET AL.
	Examiner SIMON KE	Art Unit 2174

SEARCHED			
Class	Subclass	Date	Examiner
715	780, 781	1/22/08	PK
715	780, 781	7/6/08	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	1/4/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	7/17/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	12/14/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	6/19/10	PK

SEARCH NOTES		
Search Notes	Date	Examiner
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	1/22/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	7/6/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	1/4/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	7/17/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	12/14/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	6/19/10	PK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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